

Features

- Uses CRM advanced Trench technology
- Extremely low on-resistance $R_{DS(on)}$
- Excellent $Q_g \times R_{DS(on)}$ product(FOM)
- Qualified according to JEDEC criteria

Product Summary

V_{DS}	30V
$R_{DS(on)}$ typ.	23mΩ
I_D (Silicon limit)	6A

100% DVDS Tested

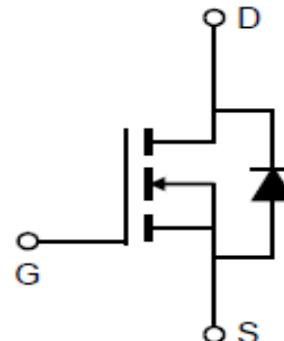
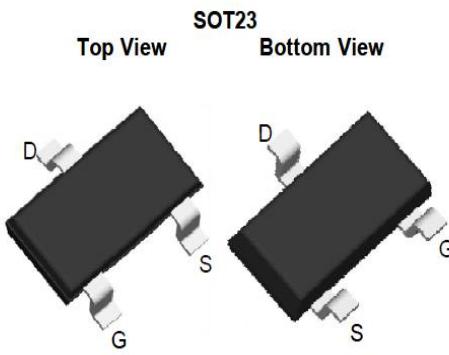
100% Avalanche Tested

Applications

- Motor control and drive
- Electrical tools
- Lithium battery protection



H F



Package Marking and Ordering Information

Part #	Marking	Package	Packing	Reel Size	Tape Width	Qty
CRTJ320N03S2-G	320N03	SOT-23	Reel	N/A	N/A	5000pcs

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Drain-source voltage	V_{DS}	30	V
Continuous drain current $T_A = 25^\circ\text{C}$ (Silicon limit) ^{a1} $T_A = 100^\circ\text{C}$ (Silicon limit)	I_D	6 3.8	A
Pulsed drain current ($T_A = 25^\circ\text{C}$, t_p limited by T_{jmax})	I_D pulse	24	A
Avalanche energy, single pulse ($L=0.5\text{mH}$)	E_{AS}	12	mJ
Gate-Source voltage	V_{GS}	± 20	V
Power dissipation ($T_A = 25^\circ\text{C}$)	P_{tot}	1.4	W
Operating junction and storage temperature	T_j , T_{stg}	-55...+150	°C
Soldering temperature, wave soldering only allowed at leads (1.6mm from case for 10s)	T_{sold}	260	°C

Thermal Resistance

Parameter	Symbol	Typ	Max	Unit
Thermal resistance, junction – ambient(min. footprint)	R _{thJA} ^{a2}	-	89	

Electrical Characteristic (at T_j = 25 °C, unless otherwise specified)

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		

Static Characteristic

Drain-source breakdown voltage	BV _{DSS}	30	-	-	V	V _{GS} =0V, I _D =250uA
Gate threshold voltage	V _{GS(th)}	0.5	0.8	1.4	V	V _{DS} =V _{GS} , I _D =250uA
Zero gate voltage drain current	I _{DSS}	-	-	1	µA	V _{DS} =30V, V _{GS} =0V T _j =25°C
		-	-	100		T _j =150°C
Gate-source leakage current	I _{GSS}	-	-	±12	nA	V _{GS} =±20V, V _{DS} =0V
Drain-source on-state resistance	R _{DS(on)}	-	23	29	mΩ	T _j =25°C V _{GS} =10V, I _D =5.8A
		-	25	31		V _{GS} =4.5V, I _D =5A
Transconductance	g _{fs}		14.4		S	V _{DS} =5V, I _D =4A

Dynamic Characteristic

Input Capacitance	C _{iss}	-	372	-	pF	V _{GS} =0V, V _{DS} =15V f=1MHz
Output Capacitance	C _{oss}	-	52	-		
Reverse Transfer Capacitance	C _{rss}	-	43	-		
Gate Total Charge	Q _g	-	4.2	-	nC	V _{GS} =4.5V, V _{DS} =15V ID=5.8A f=1MHz
Gate-Source charge	Q _{gs}	-	0.7	-		
Gate-Drain charge	Q _{gd}	-	1.48	-		
Turn-on delay time	t _{d(on)}	-	5.16	-	ns	V _{GS} =10V, RG=3.0Ω V _{DS} =15V, RL=2.7Ω
Rise time	t _r	-	2.88	-		
Turn-off delay time	t _{d(off)}	-	18.8	-		
Fall time	t _f	-	2.64	-		
Gate resistance	R _G	-	2.9	-	Ω	V _{GS} =0V, V _{DS} =0V f=1MHz

Body Diode Characteristic

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Body Diode Forward Voltage	V _{SD}	-	-	1.2	V	V _{GS} =0V, I _{SD} =5.8A
Body Diode Continuous Forward Current	I _S	-	-	6	A	T _C = 25°C
Body Diode Reverse Recovery Time	t _{rr}	-	19.8	-	ns	I _F =5A, dI/dt=100A/μs
Body Diode Reverse Recovery Charge	Q _{rr}	-	6.47	-	nC	

a1: Calculated continuous current based on maximum allowable junction temperature. Note that current limitations arising from heating of the device leads may occur with some lead mounting arrangements.

a2: The value of R_{thJA} is measured by placing the device in a still air box which is one cubic foot.

Typical Performance Characteristics

Fig 1: Output Characteristics

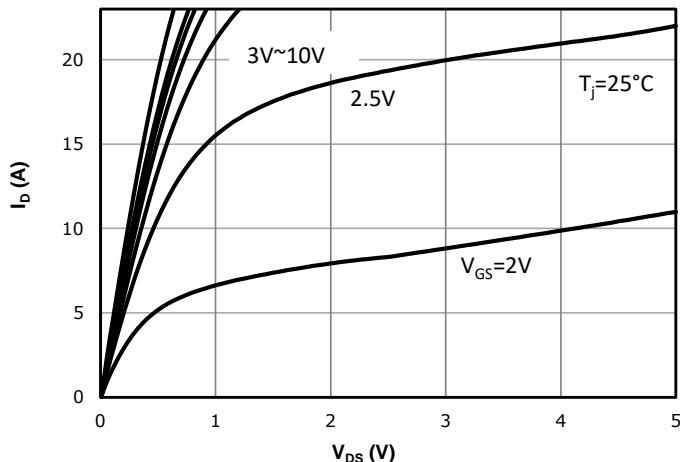


Fig 2: Transfer Characteristics

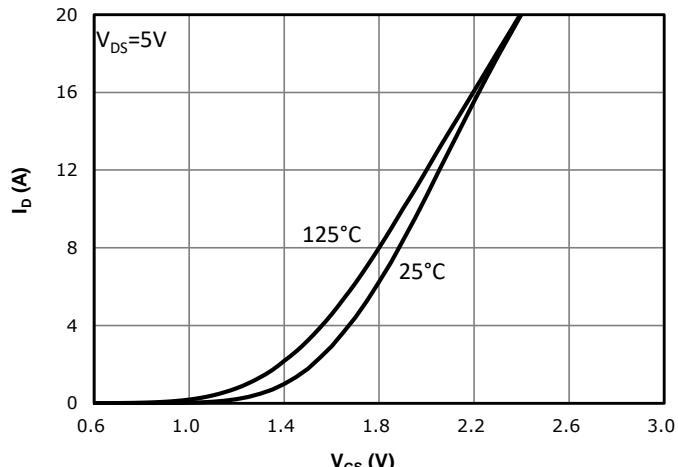


Fig 3: $R_{DS(on)}$ vs Drain Current and Gate Voltage

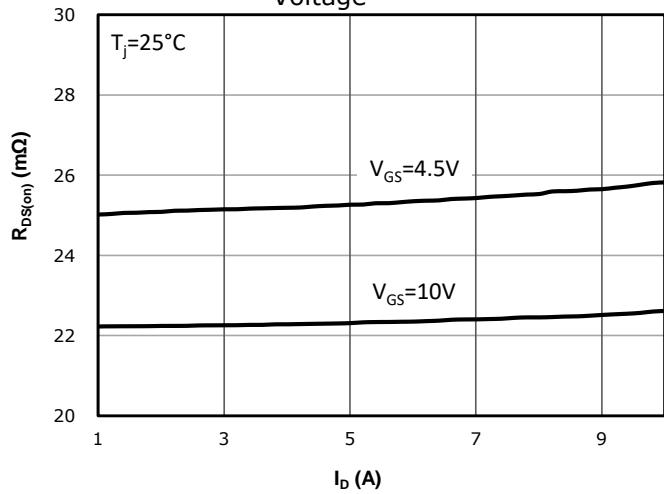


Fig 4: $R_{DS(on)}$ vs Gate Voltage

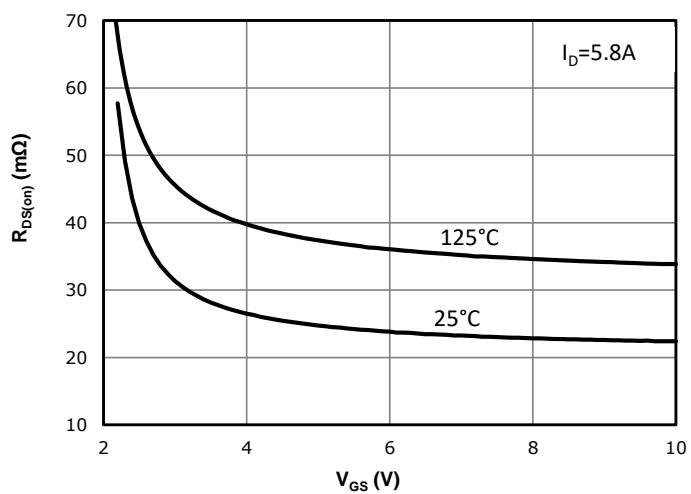


Fig 5: $R_{DS(on)}$ vs. Temperature

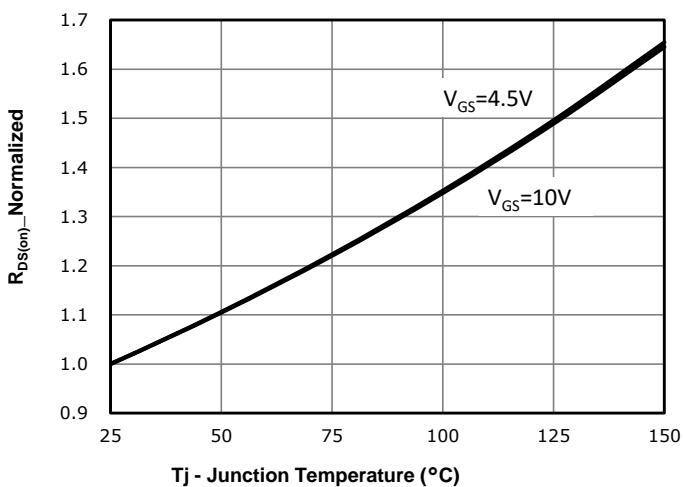


Fig 6: $V_{gs(th)}$ vs. Temperature

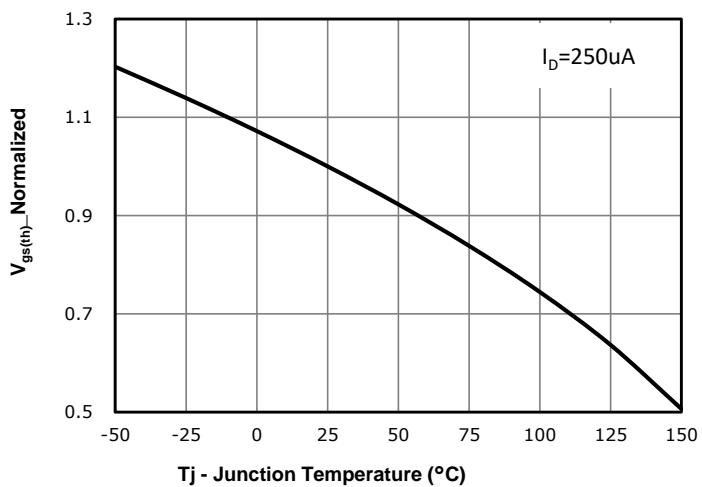


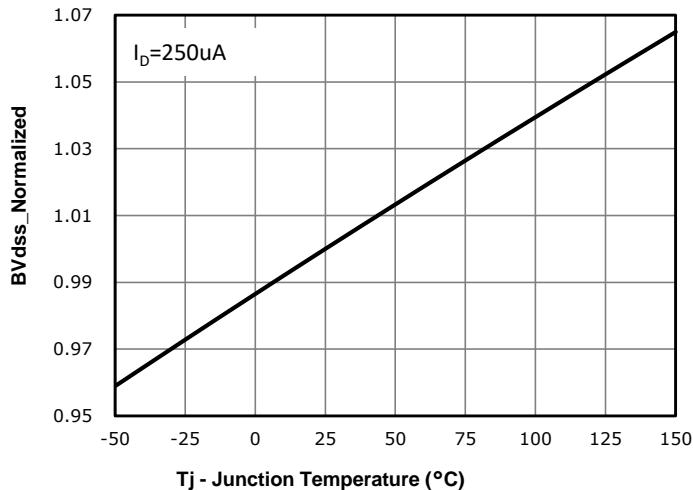
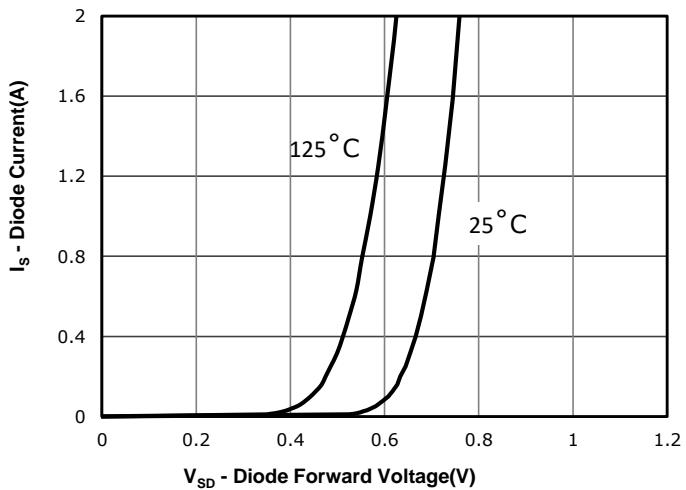
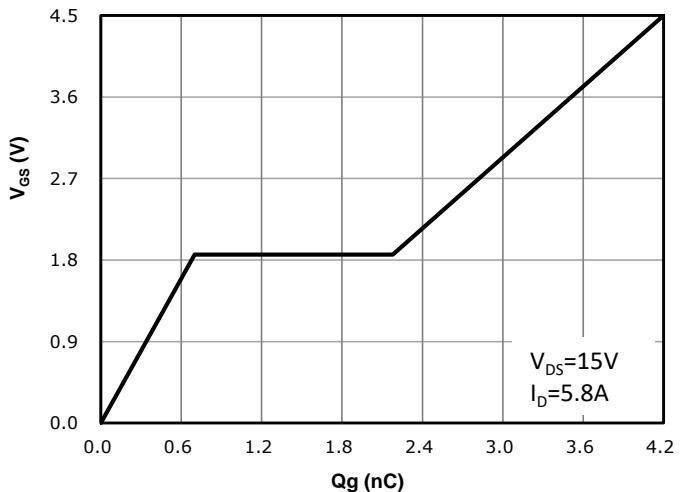
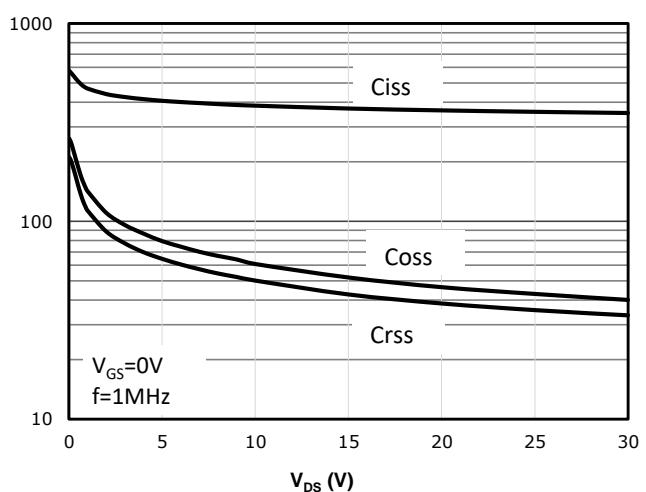
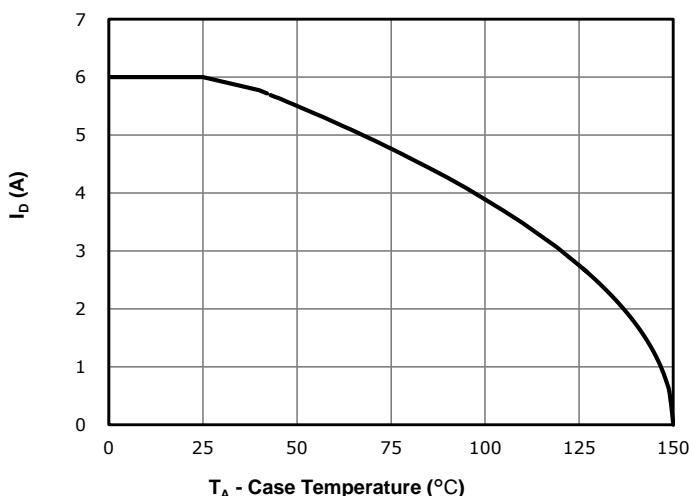
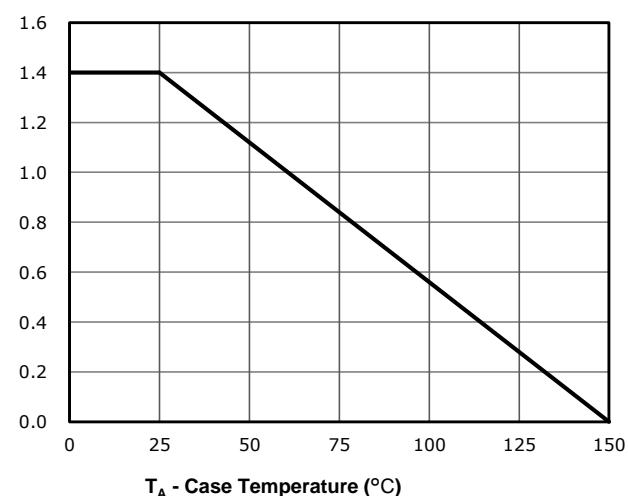
Fig 7: BV_{dss} vs. Temperature

Fig 8: Body-diode Forward Characteristics

Fig 9: Gate Charge Characteristics

Fig 10: Capacitance Characteristics

Fig 11: Drain Current Derating

Fig 12: Power Dissipation


Fig 13: Safe Operating Area

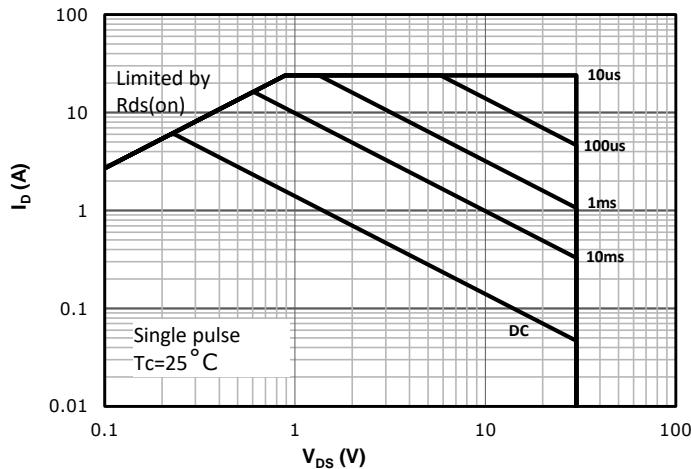
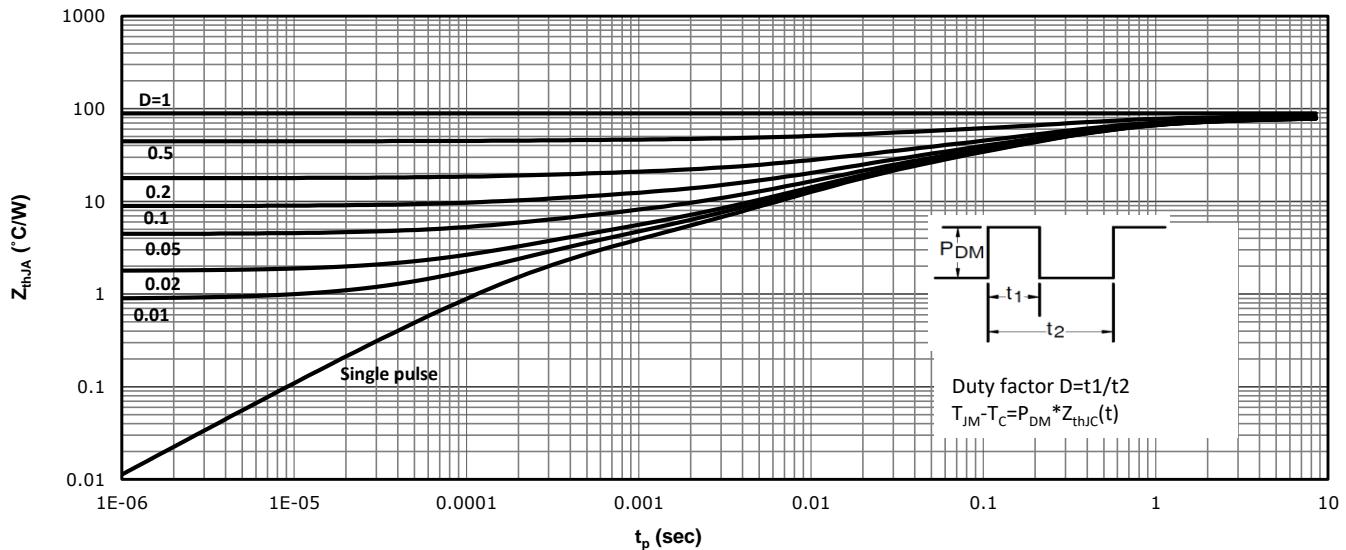
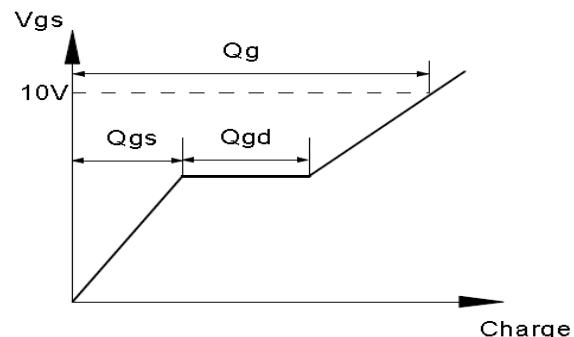
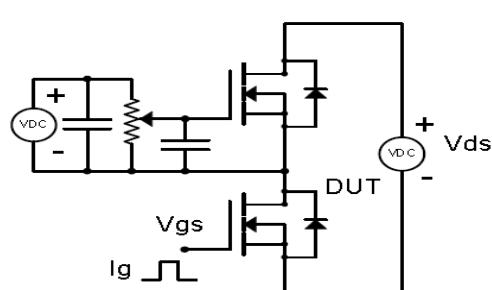


Fig 14: Max. Transient Thermal Impedance

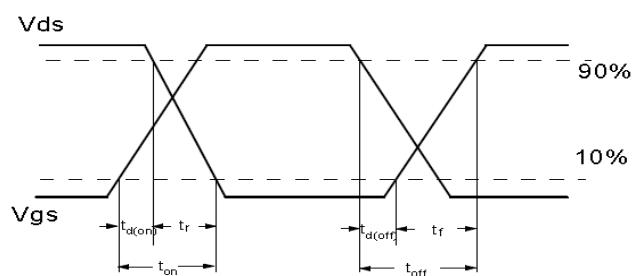
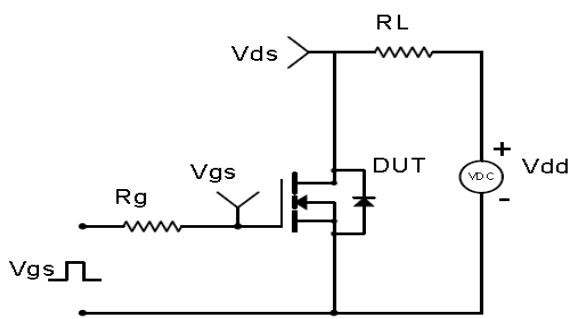


Test Circuit & Waveform

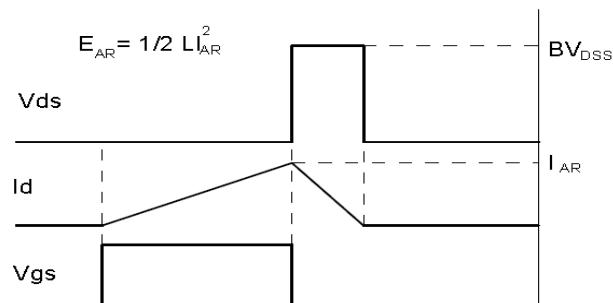
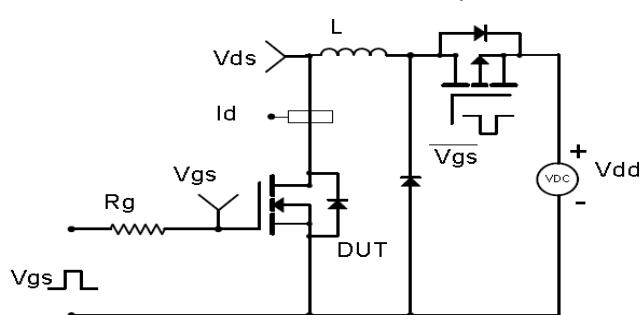
Gate Charge Test Circuit & Waveform



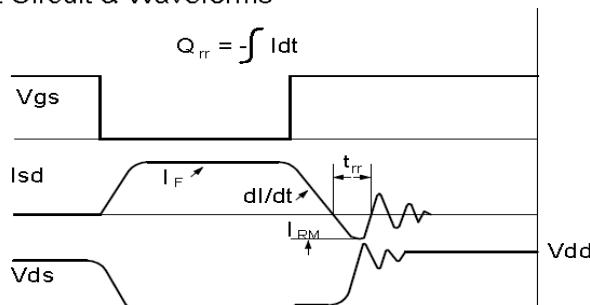
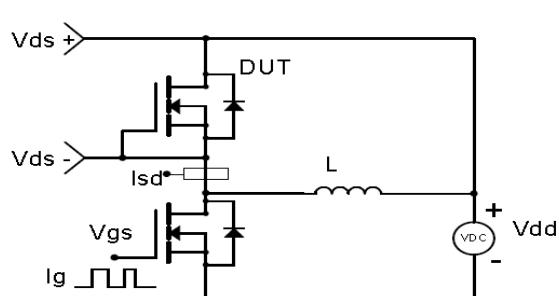
Resistive Switching Test Circuit & Waveforms

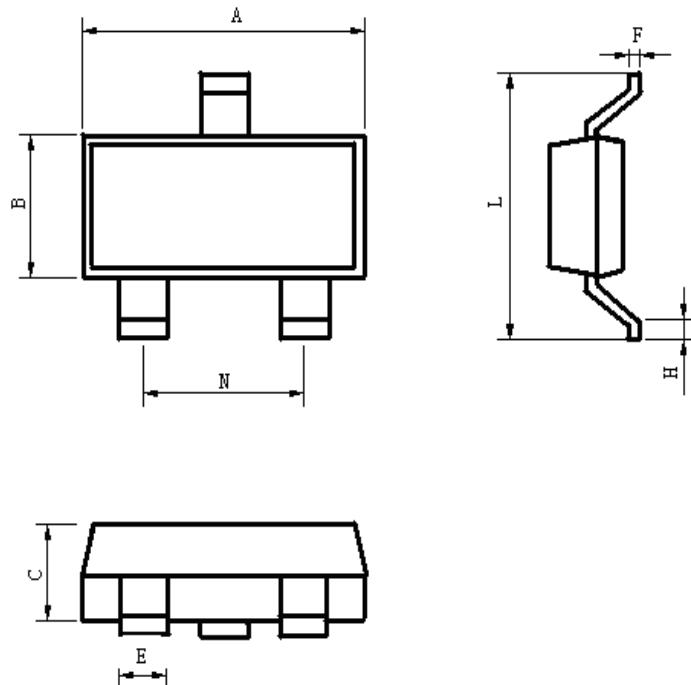


Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

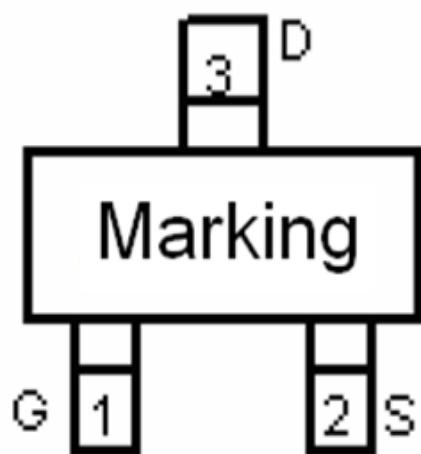


Diode Recovery Test Circuit & Waveforms



Package Outline: SOT-23


Symbol	Values(mm)	
	Min.	Max.
A	2.70	3.10
B	1.10	1.50
C	0.90	1.10
E	0.25	0.55
F	0.07	0.23
H	0.25	0.55
L	2.20	2.60
N	1.80	2.00

Marking



Revision History

Revison	Date	Major changes
1.0	2022/8/5	Relaease of formal version
2.0		
3.0		

Disclaimer

Unless otherwise specified in the datasheet, the product is designed and qualified as a standard commercial product and is not intended for use in applications that require extraordinary levels of quality and reliability, such as automotive, aviation/aerospace and life-support devices or systems.

Any and all semiconductor products have certain probability to fail or malfunction, which may result in personal injury, death or property damage. Customer are solely responsible for providing adequate safe measures when design their systems.

CRM reserves the right to improve product design, function and reliability without notice.